
Laser techniques for advanced accelerator researches:

EO sampling technique for femtosecond beam characterization

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Outline

- **Motivation**

 - The need for ultrafast beams

 - Tradition techniques

- **Current EO Technique and limitation**

 - Mechanism

 - Characteristics

 - Current status and limitation

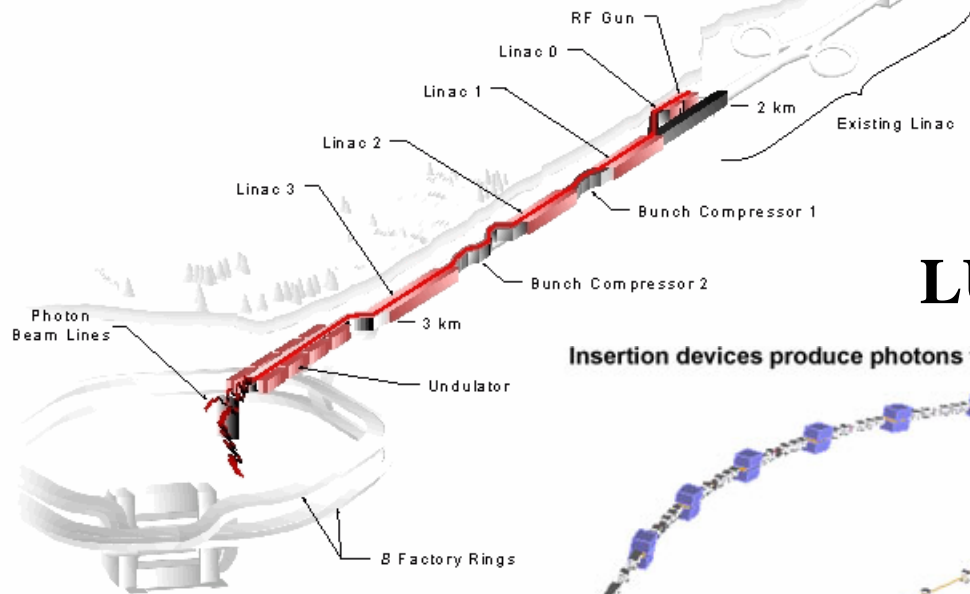
- **A phantom experiment and the FROG tech**

 - The phantom and the method

 - The experiment plan

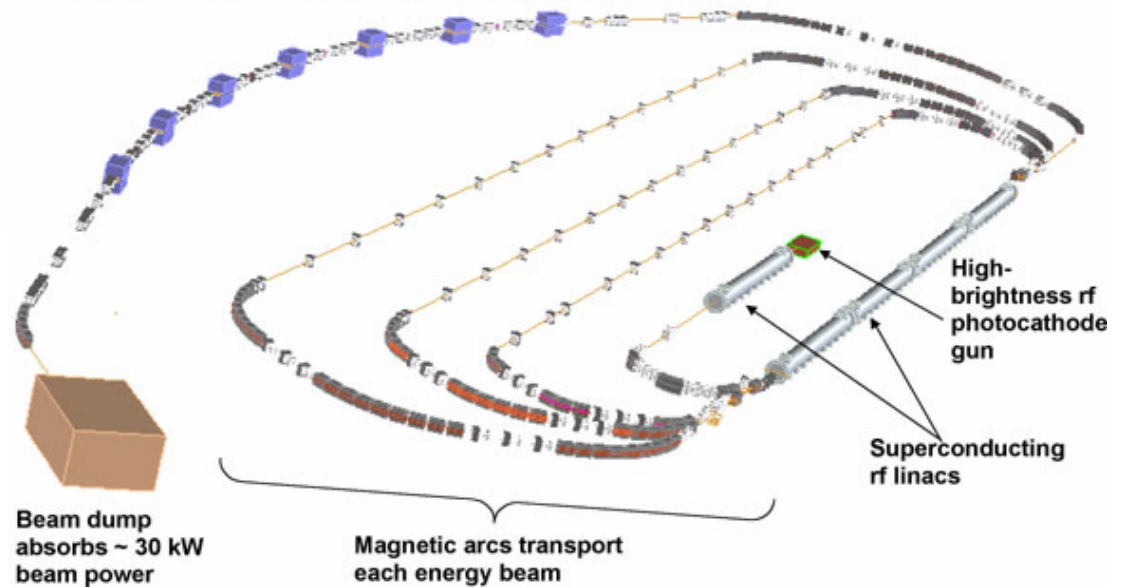
The need for ultrafast beams

LCLS: 200 fs FWHM @ 15 GeV



LUX: 20 fs EUV @ 3 GeV

Insertion devices produce photons from 3 GeV beam



Some of the methods

INVASIVE

- **RF zero phasing**

Wang et al, Phys. Rev. E 57, 2283–2286 (1998)

- **Beam tomography**

Yakimenko et al., PRSTAB 6, 122801 (2003)

Limited by rf voltage and frequency
Complexity in the energy distribution
Multiple shots

NON-INVASIVE

- **Coherent radiation transition**

Lumpkin et al., PRL 88, 234801 (2002)

- **Streak camera**

Lumpkin et al., PRL 82, 3605 (1999)

Beam profile is assumed not measured

Multiple shot, time resolution at 1 ps

MISC

- **Compton scattering**

Leemans, PRL 77, 4182 (1996)

- **Spectrum statistics**

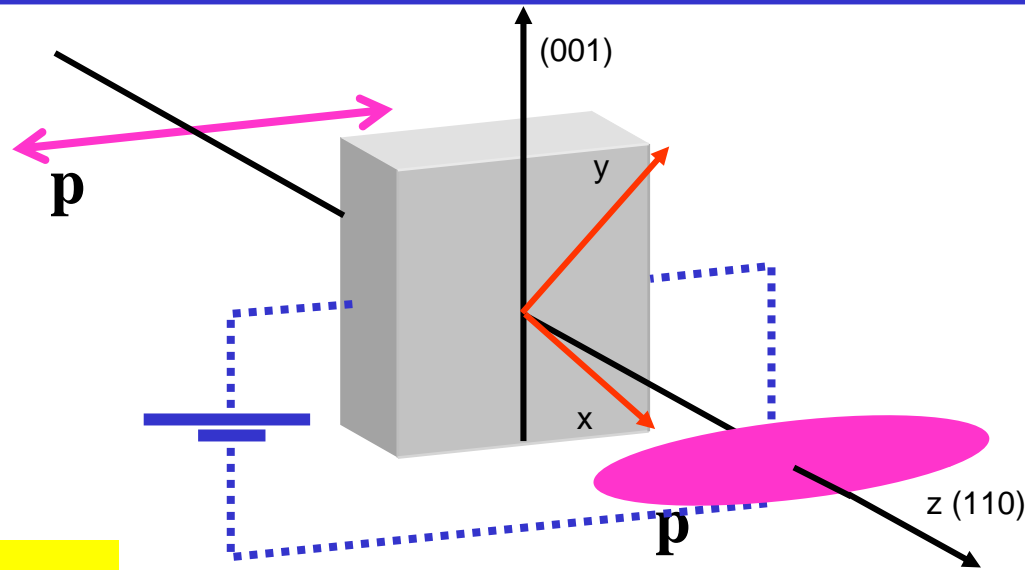
Catravas, PRL 82, 5261 (1999)

Complexity set up
Multiple shots

Multiple shots

High spectrum resolution

EO Sampling technique: Pockel's effect (ZnTe)



$$n_x = n + \frac{1}{2}n^3 E r_{41},$$

$$n_y = n - \frac{1}{2}n^3 E r_{41},$$

With a balanced
detector

$$I_x = I_p \sin^2(\phi + \delta),$$

$$I_y = I_p \sin^2(\phi - \delta),$$

$$\Delta I = I_p \sin 2\phi \sin 2\delta \equiv I_p \sin 2\delta$$

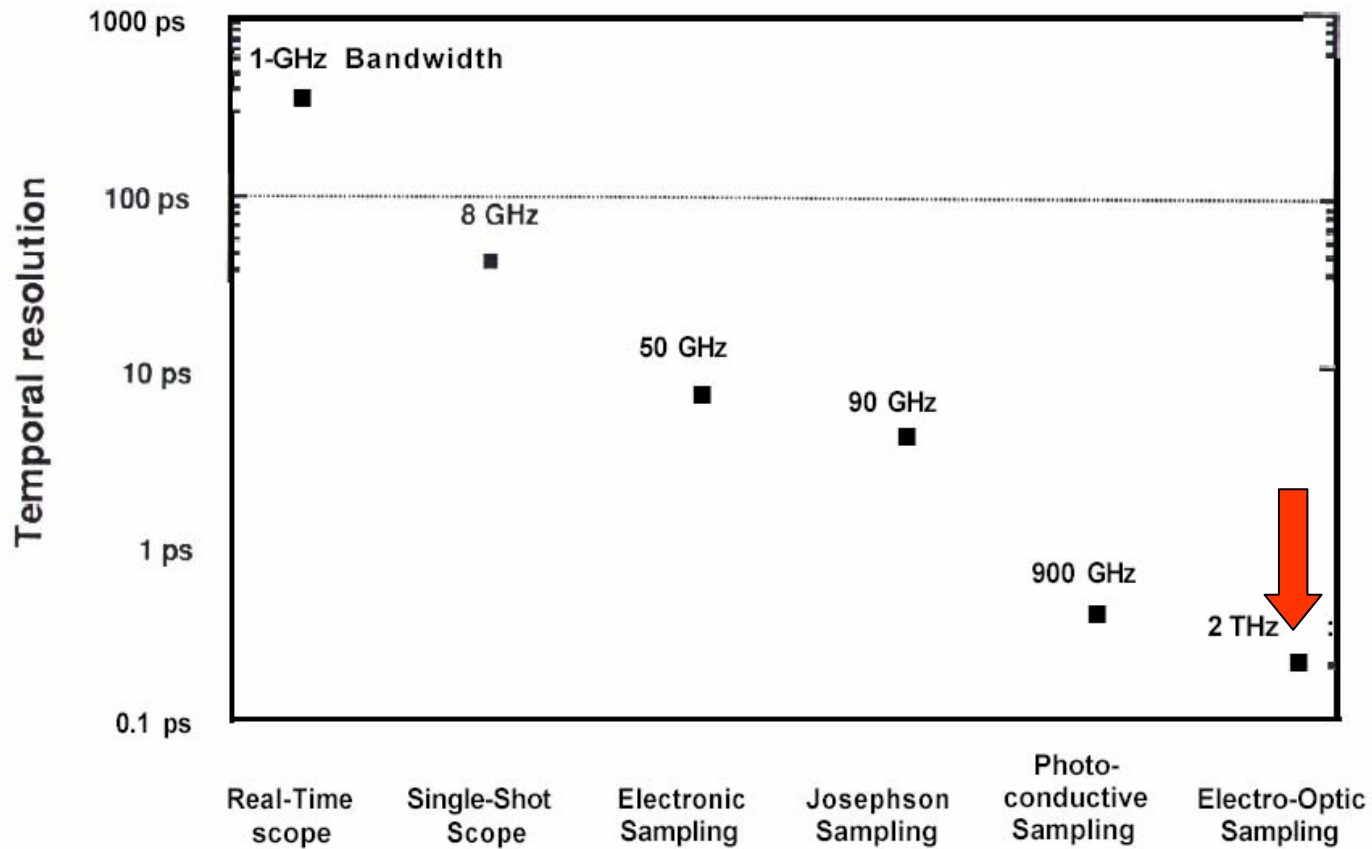
$$\delta = \frac{2\pi n^3 E r_{41}}{\lambda} = 7.27 \times 10^{-4} E l$$

$\delta \ll 1$

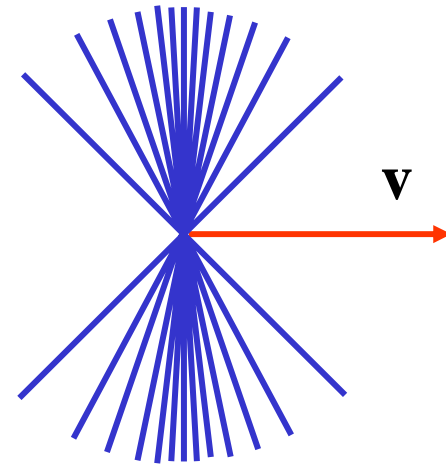
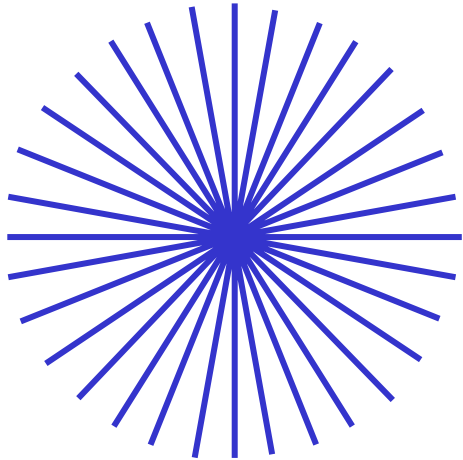
$$E \propto \frac{\Delta I}{I_p}$$

Progress in time resolution

Impact of Optics on Ultrafast Electronics



The field traveling with the beam



For a single charge q with $v=\beta c$:

$$\vec{E} = \frac{q\vec{R}}{4\pi\epsilon_0 R^3 \gamma^2 (1 - \beta^2 \sin^2 \psi)^{3/2}}.$$

For a line charge density $q(t)$ and $\gamma \gg 1$:

$$E_r(t) = \frac{q(t)}{2\pi\epsilon_0 r}.$$

Past EO e-beam measurements

Fermi lab

Fitch et al, Proc Linac 2000, 155 (2000).

Unsuccessful in generating bunch info

Brookhaven

Y. K. Semertzidis et al. *Proceedings PAC'99*, 490 (1999).

100 ps resolution.

FELIX

Yan et al., Phys. Rev. Lett. 85, 3404 (2000);

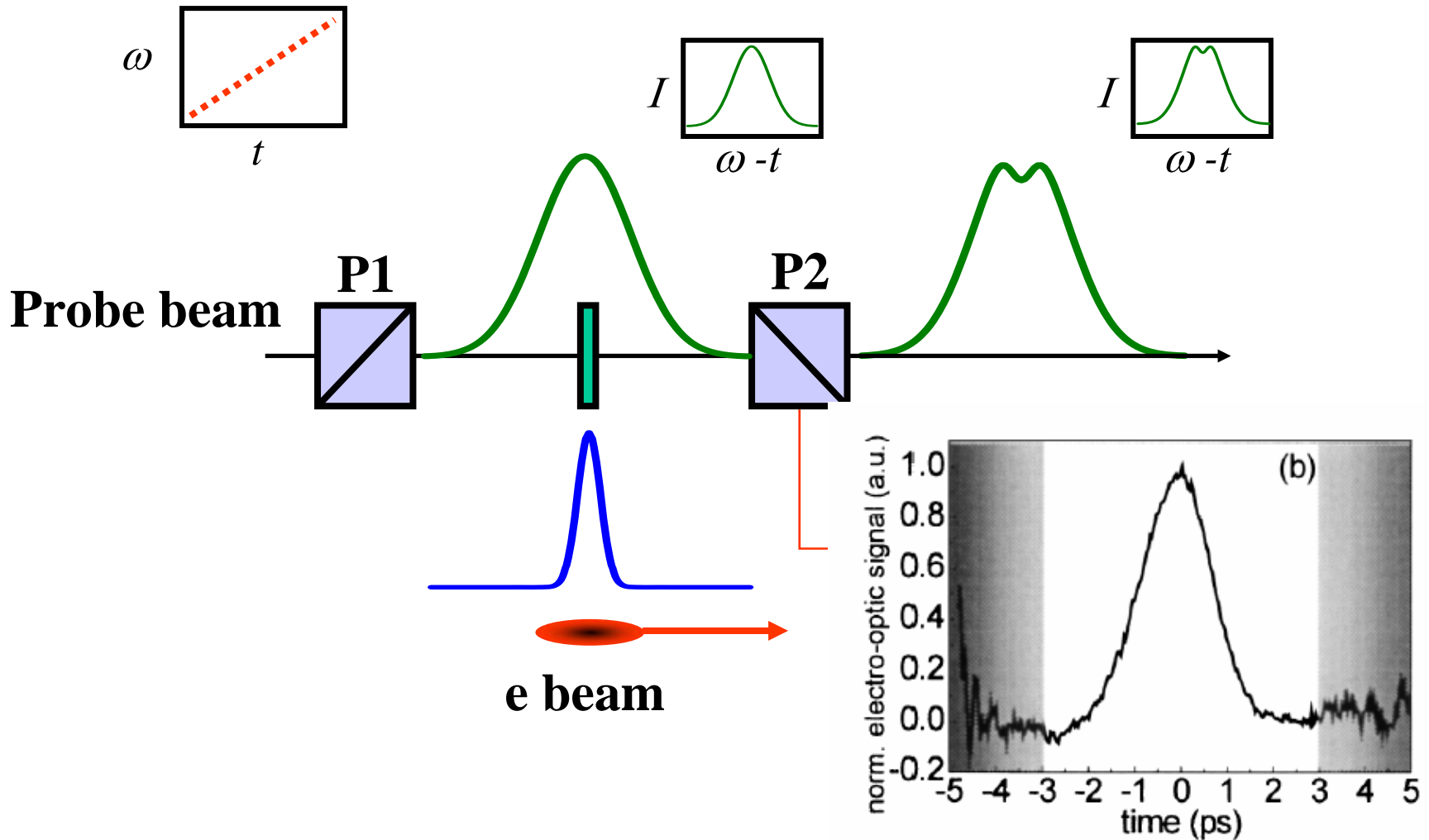
Wilke et. al., Phys. Rev. Lett. 88, 124801 (2002).

2-ps resolution.

Other institution (SPPS, DUV-FEL, GTF)

Trying

The FELIX experiment: chirped probe pulse



Temporal resolution limitation

- **Fundamental limitation: crystal response**

Thickness related, for 0.1 mm crystals

ZnTe: 5 THz; GaP: 9 THz: limited at 100 fs.

- **Fundamental limitation: bandwidth of the probe laser**

$$\Delta t \approx \sqrt{\sigma_t T}.$$

where $\sigma_t \sim 1/\sigma_\omega$.

For $\sigma_t = 100$ fs, $T = 100$ ps, $\Delta t \approx 3$ ps.

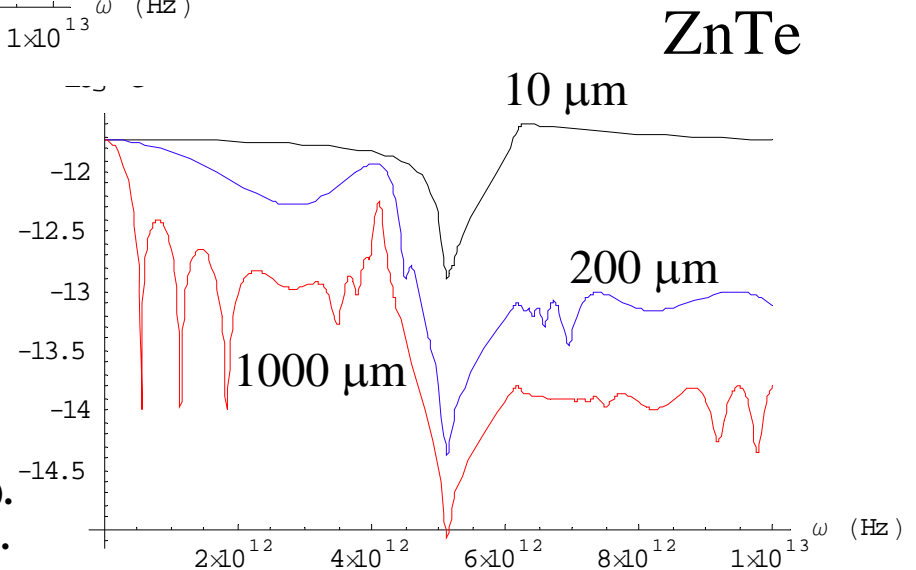
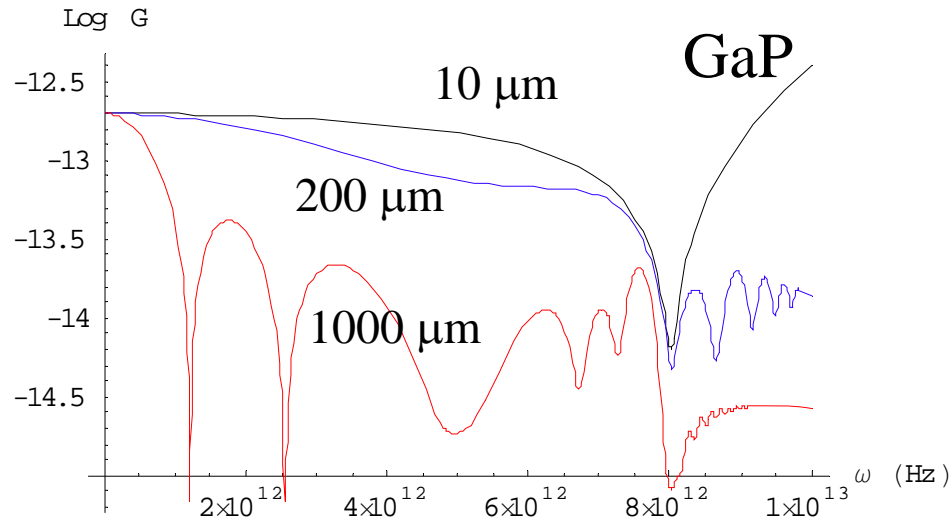
- **Geometry limitation: beam energy and distance**

$$\Delta t = r/c\gamma.$$

For APS, $\gamma = 14000$, with $r = 1$ cm, $\Delta t = 2$ fs

- **Instrumental limitation: spectral resolution**

Crystal properties



- Z. Jiang and X. C. Zhang, *IEEE J. Quantum Electron.* 36, 1214 (2000).
- H. J. Bakker et al., *JOSA B* 15, 1795 (1998).
- A. Leitenstorfer et al., *APL* 74, 1516 (1999).

Some formula

The probe pulse

$$E_{pin}(t) = \exp\left[-\frac{1}{2}\left(\frac{t}{T}\right)^2 - i\left(\omega + \frac{\sqrt{4T^2\Delta\omega^2 - 1}}{4T^2}t\right)t\right].$$

Given, electron beam field, $E(t)$ in the time domain and $E(\omega) = F[E(t)]$ in the frequency domain, and the complex response function $G(\omega)$, in the FELIX exp, one measured

$$I_{pout}(\omega) = \left|F[E_p \cdot F^{-1}(E \cdot G)]\right|^2.$$

The other possibility is to do a different measurement, to get

$$E_{pout}(t) = E_{pin}(t) \cdot E(t) * G(t).$$

Which is equivalent to intensity +phase.

How about a FROG?



= Frequency Resolved Optical Gating

Kane and Trebino, JQE, 29, 571 (1993).
DeLong and Trebino, JOSA B, 11, 2206 (1994).

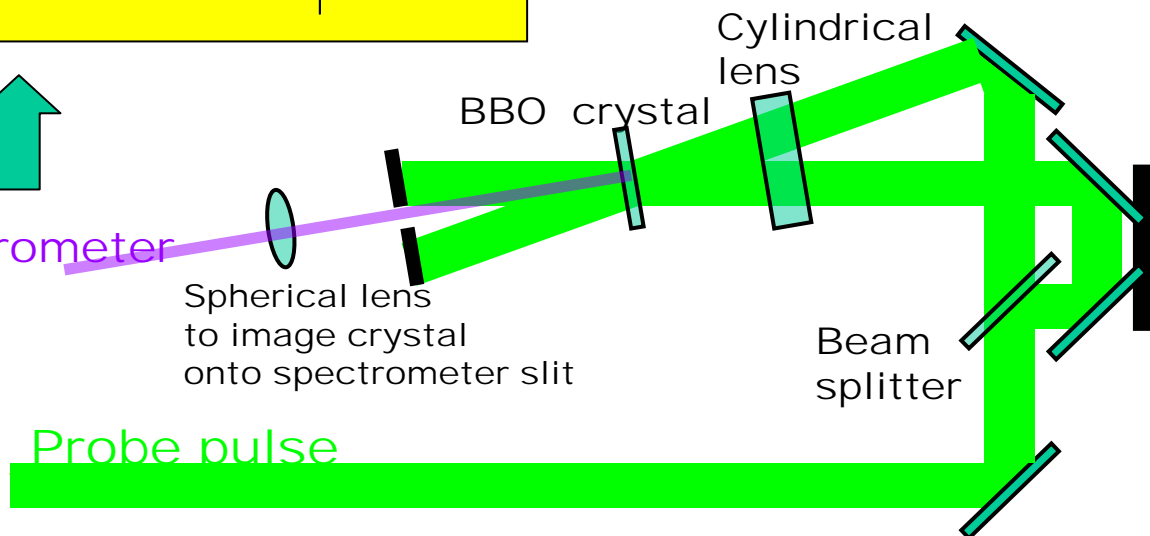
For the second harmonic FROG

$$E_{sig}(t, \tau) \propto E(t)E(t - \tau).$$

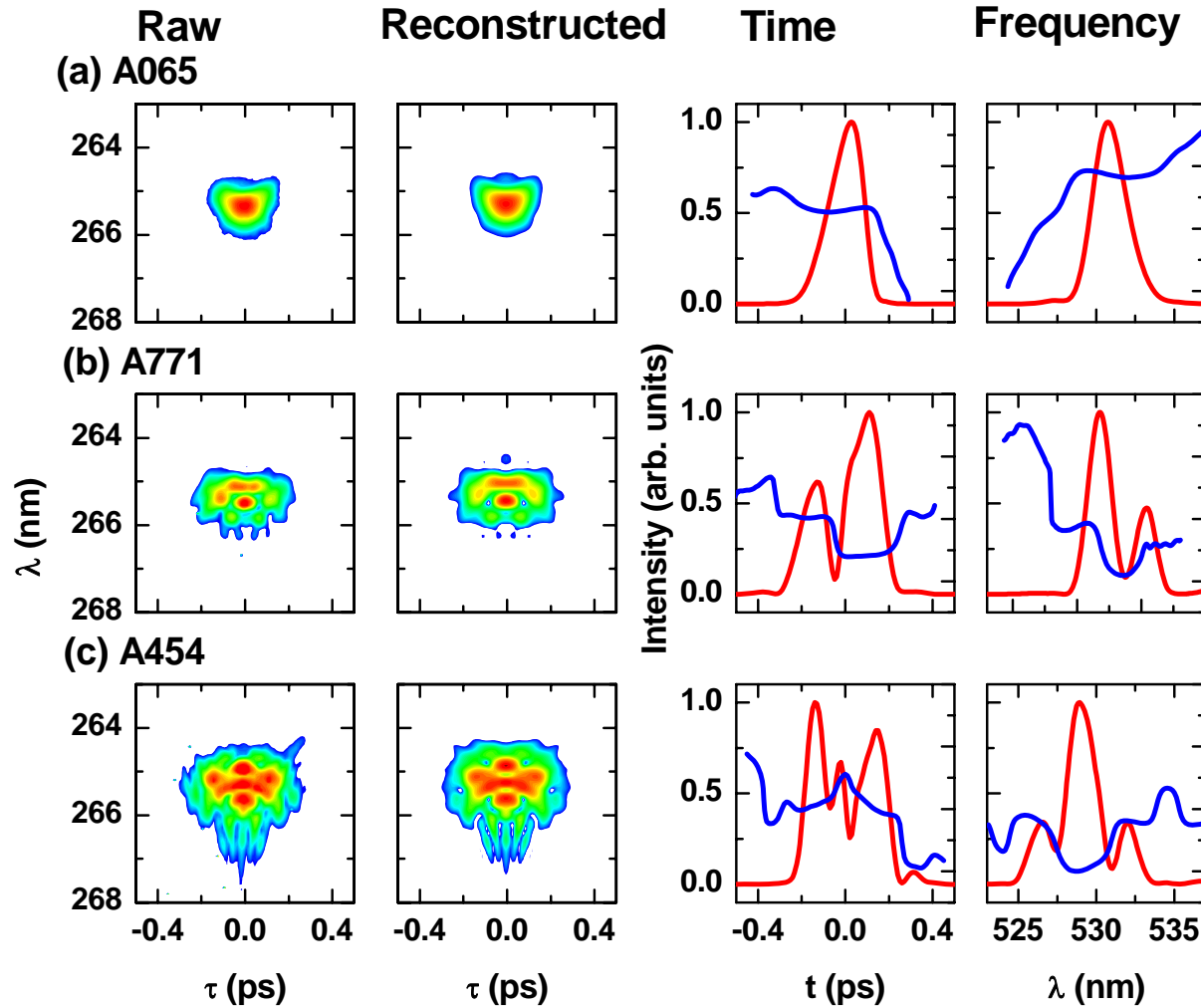
And the measured signal on the spectrometer is

$$I_{FROG}(\omega, \tau) \propto \left| \int_{-\infty}^{\infty} E_{sig}(t, \tau) \exp(-i\omega t) dt \right|^2.$$

Correlated
Signal to spectrometer

Sample traces: FEL experiment



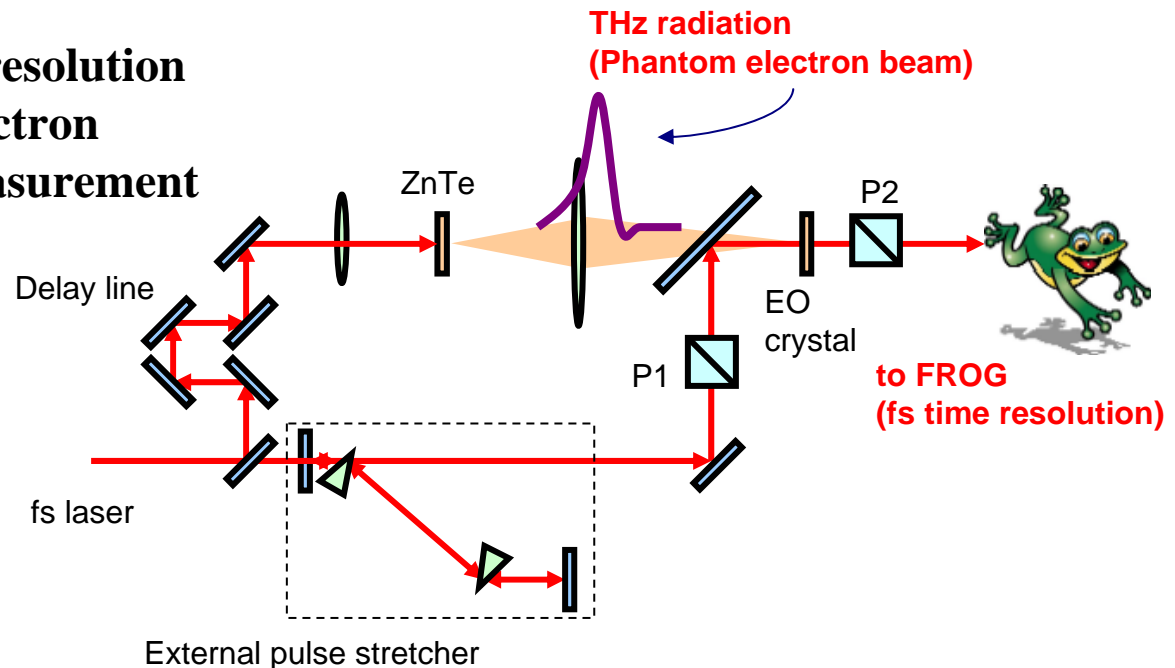
APS Experimental goal and setup

Key features

- Use laser-generated THz radiation as an electron beam phantom, in a **lab setting**
- Employ the Frequency-Resolved Optical Gating (FROG) for **single-shot fs resolution**

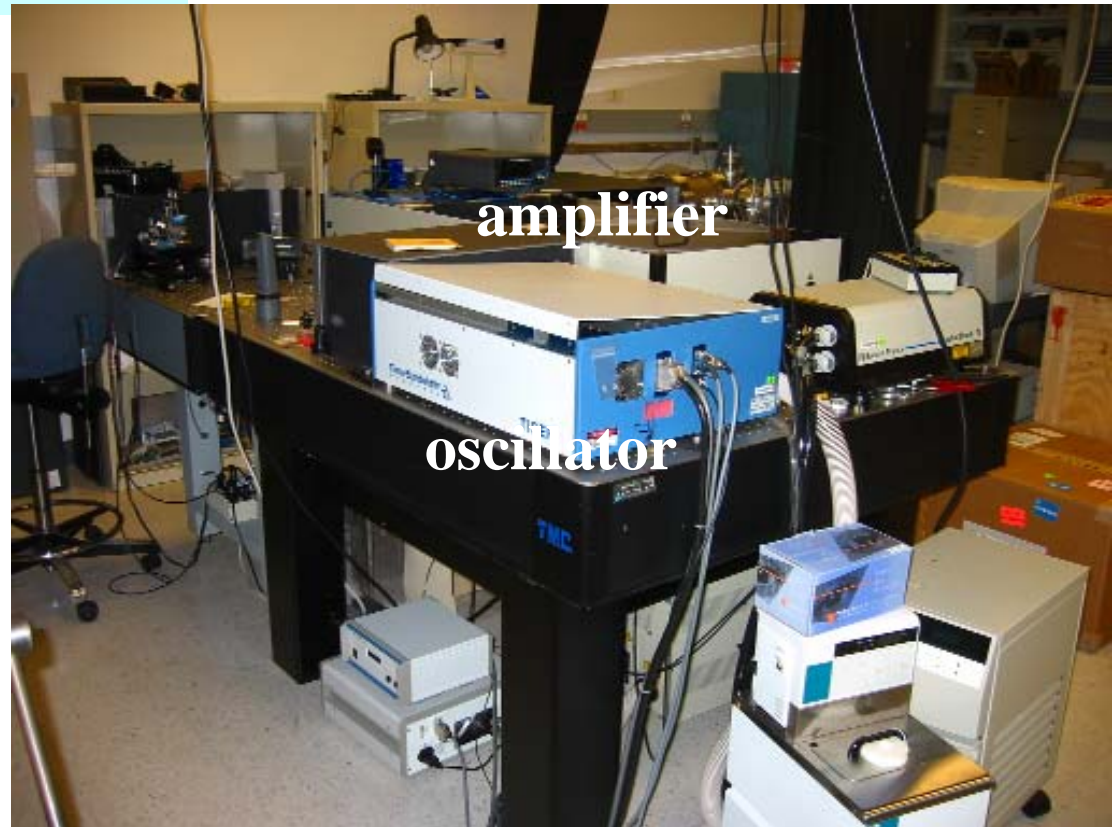
Goal

- A system with fs resolution for single shot electron bunch profile measurement



Lab

Bandwidth	16 nm
Pulse duration	70 fs
Rep Rate	1 kHz
Energy	~ mJ



Plan

Generating the phantom

Optical rectification

Z. Jiang and X. C. Zhang, *IEEE J. Quantum Electron.* 36, 1214 (2000).

H. J. Bakker et al., *JOSA B* 15, 1795 (1998).

A. Leitenstorfer et al., *APL* 74, 1516 (1999).

Probing the phantom

EO sampling + FROG

Try different crystals

Try different laser pulses

Application in the lab?